

Title (en)
APPARATUS OF PLURAL CHARGED-PARTICLE BEAMS

Title (de)
VORRICHTUNG MIT MEHREREN GELADENEN TEILCHENSTRAHLEN

Title (fr)
APPAREIL AYANT PLUSIEURS FAISCEAUX DE PARTICULES CHARGÉES

Publication
EP 3268979 A1 20180117 (EN)

Application
EP 16762718 A 20160413

Priority
US 2016027267 W 20160413

Abstract (en)
[origin: WO2016145458A1] A multi-beam apparatus for observing a sample with high resolution and high throughput is proposed. In the apparatus, a source-conversion unit changes a single electron source into a virtual multi-source array, a primary projection imaging system projects the array to form plural probe spots on the sample, and a condenser lens adjusts the currents of the plural probe spots. In the source-conversion unit, the image-forming means is on the upstream of the beamlet-limit means, and thereby generating less scattered electrons. The image-forming means not only forms the virtual multi-source array, but also compensates the off-axis aberrations of the plurality of probe spots.

IPC 8 full level
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Designated contracting state (EPC)
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WO 2016145458 A1 20160915; CN 108292583 A 20180717; CN 108292583 B 20200320; EP 3268979 A1 20180117; EP 3268979 A4 20190508; JP 2018513543 A 20180524; JP 6550478 B2 20190724

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